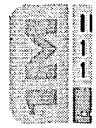


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*Landis, D.L.;*

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*Jin-Fu Li; Hsin-Jung Huang; Jeng-Bin Chen; Chih-Pin Su; Cheng-Wen Wu; Ch Cheng; Shao-I Chen; Chi-Yi Hwang; Hsiao-Ping Lin;*

Micro, IEEE , Volume: 22 , Issue: 5 , Sept.-Oct. 2002

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3 **A parallel built-in self-diagnostic method for embedded memory array**
*Der-Cheng Huang; Wen-Ben Jone;*

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction on , Volume: 21 , Issue: 4 , April 2002

Pages:449 - 465

[\[Abstract\]](#)   [\[PDF Full-Text \(475 KB\)\]](#)   **IEEE JNL**
4 **Oscillation-test methodology for low-cost testing of active analog devices**
*Arabi, K.; Kaminska, B.;*

Instrumentation and Measurement, IEEE Transactions on , Volume: 48 , Issue: 4 , Aug. 1999

Pages:798 - 806

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[Abstract] [PDF Full-Text (180 KB)] IEEE JNL

---

**5 Full operation of a three-node pipeline-ring switching chip for a superconducting network system**

*Yorozu, S.; Hashimoto, Y.; Numata, H.; Koike, M.; Tanaka, M.; Tahara, S.;*  
Applied Superconductivity, IEEE Transactions on , Volume: 9 , Issue: 2 , June

Pages:3590 - 3593

[Abstract] [PDF Full-Text (576 KB)] IEEE JNL

---

**6 Design of Boeing 777 electric system**

*Andrade, L.; Tenning, C.;*  
Aerospace and Electronic Systems Magazine, IEEE , Volume: 7 , Issue: 7 , Ju  
1992

Pages:4 - 11

[Abstract] [PDF Full-Text (652 KB)] IEEE JNL

---

**7 An implantable CMOS circuit interface for multiplexed microelectrode recording arrays**

*Ji, J.; Wise, K.D.;*  
Solid-State Circuits, IEEE Journal of , Volume: 27 , Issue: 3 , March 1992  
Pages:433 - 443

[Abstract] [PDF Full-Text (904 KB)] IEEE JNL

---

**8 Designing in power-down test circuits**

*Levy, P.S.;*  
Design & Test of Computers, IEEE , Volume: 8 , Issue: 3 , Sept. 1991  
Pages:31 - 35

[Abstract] [PDF Full-Text (288 KB)] IEEE JNL

---

**9 Serial interfacing for embedded-memory testing**

*Nadeau-Dostie, B.; Silburt, A.; Agarwal, V.K.;*  
Design & Test of Computers, IEEE , Volume: 7 , Issue: 2 , April 1990  
Pages:52 - 63

[Abstract] [PDF Full-Text (784 KB)] IEEE JNL

---

**10 A 16-Mbit/s adapter chip for the IBM token-ring local area network**

*Blair, J.D.; Correale, A., Jr.; Cranford, H.C.; Dombrowski, D.A.; Erdelyi, C.K.;*  
*Hoffman, C.R.; Lamphere, J.L.; Lang, K.W.; Lee, J.K.; Mullen, J.M.; Norman,*  
*Oakland, S.F.;*  
Solid-State Circuits, IEEE Journal of , Volume: 24 , Issue: 6 , Dec. 1989  
Pages:1647 - 1655

[Abstract] [PDF Full-Text (840 KB)] IEEE JNL

---

**11 Off-chip  $I_{ddq}$  monitor with standard test interface**

*Pedros, J.; Rubio, A.;*  
Electronics Letters , Volume: 31 , Issue: 14 , 6 July 1995

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Pages:1139 - 1140

[\[Abstract\]](#) [\[PDF Full-Text \(192 KB\)\]](#) **IEE JNL**

---

**12 Robust/low cost SSPCs are finally available**

*Friedman, S.;*

Digital Avionics Systems Conference, 1997. 16th DASC., AIAA/IEEE , Volume 2 , 26-30 Oct. 1997

Pages:7.3 - 31-7.3-36 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(468 KB\)\]](#) **IEEE CNF**

---

**13 Boundary scan access of built-in self-test for field programmable g arrays**

*Gibson, G.; Gray, L.; Stroud, C.;*

ASIC Conference and Exhibit, 1997. Proceedings., Tenth Annual IEEE International , 7-10 Sept. 1997

Pages:57 - 61

[\[Abstract\]](#) [\[PDF Full-Text \(512 KB\)\]](#) **IEEE CNF**

---

**14 A smart sensing microsystem with a capacitive sensor interface**

*Yazdi, N.; Mason, A.; Najafi, K.; Wise, K.D.;*

Circuits and Systems, 1996. ISCAS '96., 'Connecting the World'. , 1996 IEEE International Symposium on , Volume: 4 , 12-15 May 1996

Pages:336 - 339 vol.4

[\[Abstract\]](#) [\[PDF Full-Text \(364 KB\)\]](#) **IEEE CNF**

---

**15 Development of on-line diagnosis system using intelligent devices semiconductor equipment**

*Noguchi, T.; Aizono, T.; Kawano, K.; Ohashi, M.; Kogure, M.;*

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-2002

Pages:3246 - 3250 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(353 KB\)\]](#) **IEEE CNF**

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